

### A Cost-Effective FPGA-based Fault Simulation Environment

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- 1. Motivation
- 2. FPGA-Based Fault Simulation Environment
- 3. ECC Case Study



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### Motivation



#### Fault attacks - Attackers inject faults to recover secrets.

- Glitches in power or clock supply.
- Optical attacks (e.g., laser).



#### Powerful threat for cryptographic implementations.





Physical level.
 Voltage, light sensors.



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#### Countermeasures must be verified.

# Verification of Countermeasures



#### Laboratory.

- Late in design flow.
- Highly complicated.
- Difficult to reach high coverage.

# Verification of Countermeasures



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- Highly complicated.
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#### Simulation.

- Earlier in design flow.
- ► Fault models for abstraction.
- ► High performance and coverage possible.



Two choices for hardware simulation.

- 1. Software-based simulation.
  - Performance low for large designs.
- 2. FPGA-based simulation.
  - Performance high.



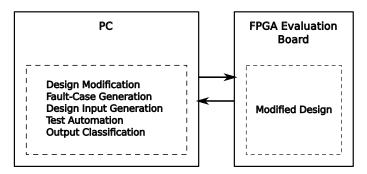
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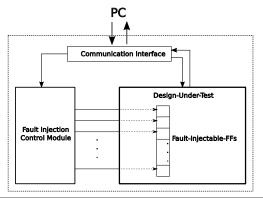
#### For digital hardware designs of cryptographic algorithms.





### Design-Under-Test (DUT) is modified through script.

- Replace flip-flops.
- Netlist.
- New top-level.
- Additional fault injection control and communication module.



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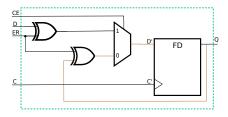
#### Flip-flop cell replacement.



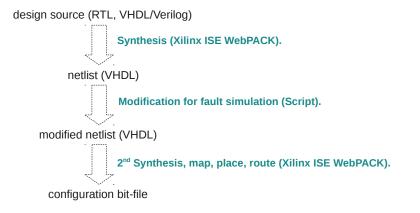


#### Flip-flop cell replacement.











Fault model specific for fault attacks.

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#### Fault model specific for fault attacks.

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- Complete timing control.
- Complete location control.
  All single or multi-bit faults.
- Bit flip effect.
- ► Transient (one cycle) fault duration.

Fault model can be further restricted.



#### Fault-case generation automated.

- Requires list of fault-injectable flip-flops.
- Requires fault configuration.
- Outputs list of fault test cases.
  If space to large, random choice of subset.



#### Simulation is automated.



- 1. FPGA configured with modified design.
- 2. All fault cases are performed. For every case:



#### Simulation is automated.



- 1. FPGA configured with modified design.
- 2. All fault cases are performed. For every case:
  - ► Fault injection control module re-configuration.
  - Start simulation.
  - Collect output and store testcase outcome.

#### 

#### Available information.

- DUT output vs. expected output.
- DUT status indication.
- Timing compliance.

Eraunhofer

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- DUT output vs. expected output.
- DUT status indication.
- Timing compliance.

#### Fault case simulation outcome.

- 1. Silent still correct.
- 2. Detected detected fault.
- 3. Fault faulty result output.
- 4. Timeout No response.



- **FPGA-based for high performance**.
- Supports Verilog and VHDL designs.
- Automated modification on netlist no design effort.
- Cost-effective Tooling.



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#### DUT =

Digital hardware design of Elliptic Curve Scalar Multiplication.

- Countermeasure against fault attacks: point validity check at the end of computation.
  - $\rightarrow$  This countermeasure is evaluated.

# Fault Model Configuration ECC Case Study



#### Fault model configuration:

- Derived from fault attacks on ECC.
- Every clock cycle during ECSM.
  - ▶ 95,000 cycles.
- ► Transient (one cycle) faults.
- Bit-flip fault effect.
- Single bit (to simplify case study) faults in all registers.
  Split simulation in two parts:
  - 1,600 data-path flip-flops.
  - 90 control-path flip-flops.



#### Fault injection hardware overhead for DUT $\sim+25\,\%.$

### Simulation performance of 16 ms per test-case.

- DUT at 50 MHz.
- ▶ RS232 transmission more than **70%**.



Simulation in two parts:

- Control-path flip-flops.
  - $\sim$  9 million test-cases.
  - 100 % coverage.
- Data-path flip-flops.
  - $\sim$  35 million test-cases.
  - 22 % coverage.



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  - 22 % coverage.

9 days of simulation  $\sim$  46 years in software simulation.



#### Control-path.

- 1 % Timeouts.
- ▶ 38% Silent faults.
- ▶ 44 % Detected faults.
- ▶ 18% Faults.

In most cases program counter was manipulated and intermediate values output.  $\rightarrow$  Serious problem.  $\rightarrow$  Countermeasure required.



#### Control-path.

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#### Data-path.

- 0 % Timeouts.
- 24 % Silent faults.
- 77 % Detected faults.

#### 0.02 % Faults.

Most changed output after point check.  $\rightarrow$  **Useless for attacker**.



- ► Speed-up of ~ 2000 compared to software simulation.
- Point validity check countermeasure proved very effective.
- However, weaknesses were successfully exposed.
  - Control path needs protection.
  - Detected faults can be used for safe-error attacks.